



**PATENT**

**THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Application No.: 10/791,629  
Filing Date: March 03, 2004  
Applicant: Soo-Chan Lee  
Group Art Unit: 2829  
Examiner: Jermele M. Hollington  
Title: SYSTEM AND METHOD FOR TESTING SEMICONDUCTOR DEVICES  
Attorney Docket: 2421-000033/US

Customer Service Window  
Randolph Building  
401 Dulany Street  
Alexandria, VA 22314  
**Mail Stop Amendment AF**

December 4, 2006

**AMENDMENT AFTER FINAL**

Sir:

In response to the Final Office Action mailed October 3, 2006, the following remarks are respectfully submitted in connection with the above-identified application.

**Listing of the Claims** begin on page 2 of this Amendment.

**Remarks** begin on page 15 of this Amendment.

	Claims remaining after Amendment		Highest number previously paid for		Present extra
Total	40	-	42	=	0
Independent	13	-	13	=	0

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